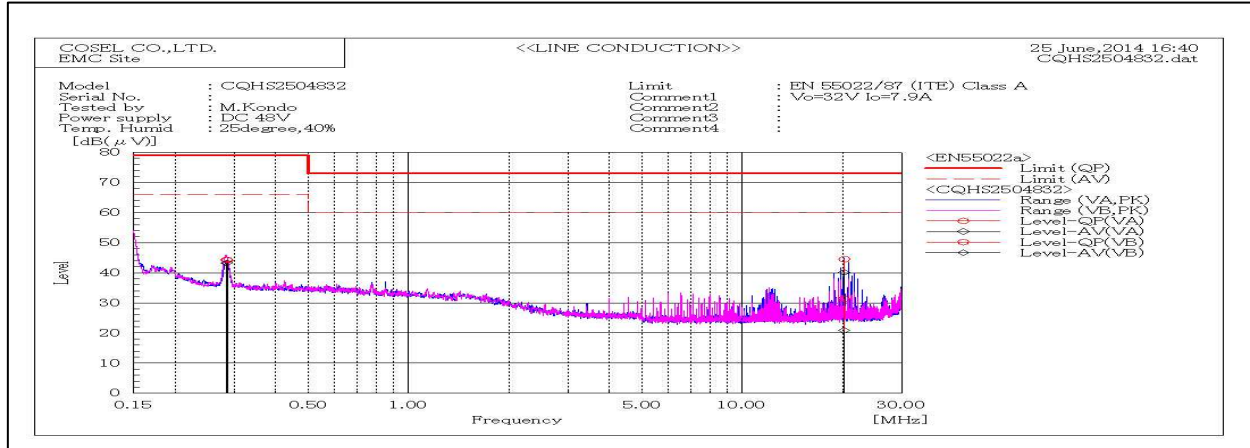
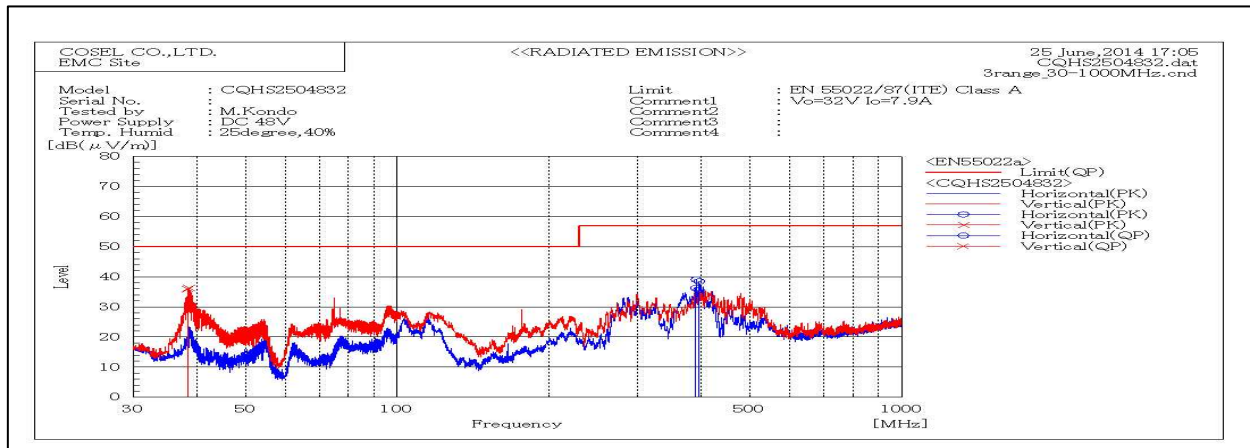


DATA SHEET		Date	25-Jun-14
Model	CQHS2504832	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



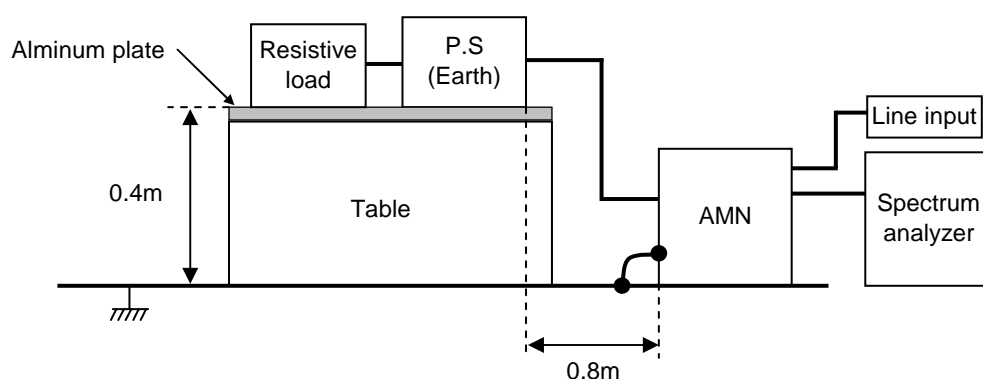
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.28498		VA	24.2	23.2	20.1	44.3	43.3	79	66	34.7	22.7	Pass	
0.28631		VB	24.1	23.2	20.1	44.2	43.3	79	66	34.8	22.7	Pass	
20.23565		VA	23.5	19.2	21	44.5	40.2	73	60	28.5	19.85	Pass	
20.20425		VB	10.4	-0.2	21	31.4	20.8	73	60	41.6	39.2	Pass	



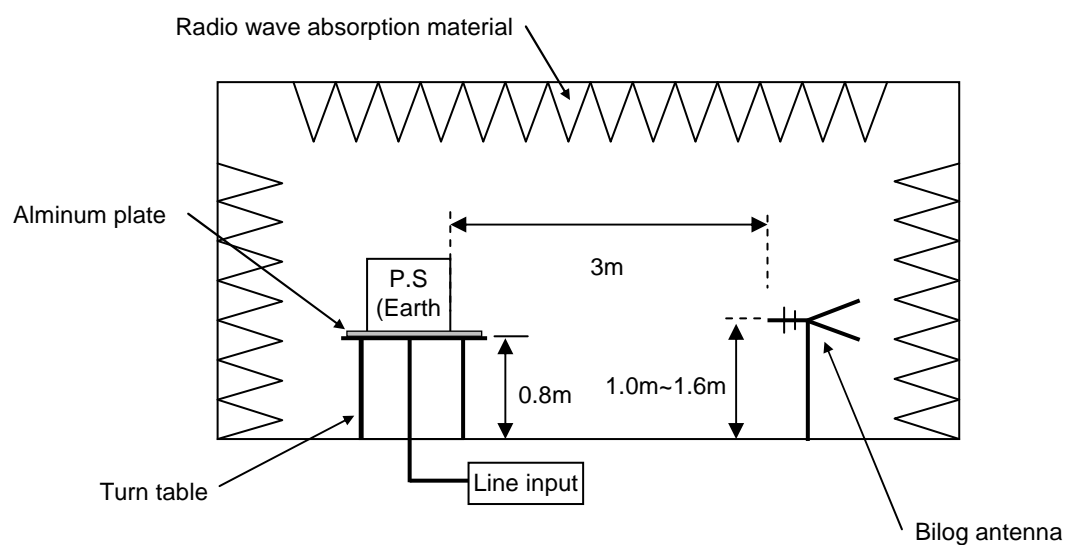
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
38.425	V	Stable	51.1	-15.3	35.8	50	14.2	Pass	105	71	
391.144	H	Stable	48.4	-12.1	36.3	57	20.7	Pass	103	168	
396.32	H	Stable	47.3	-11.6	35.7	57	21.3	Pass	101	177	

DATA SHEET		Date	25-Jun-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission

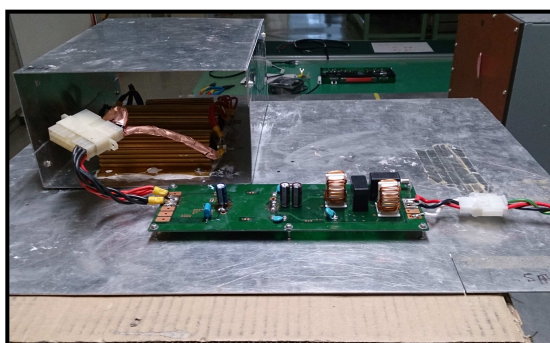


Test: EMI

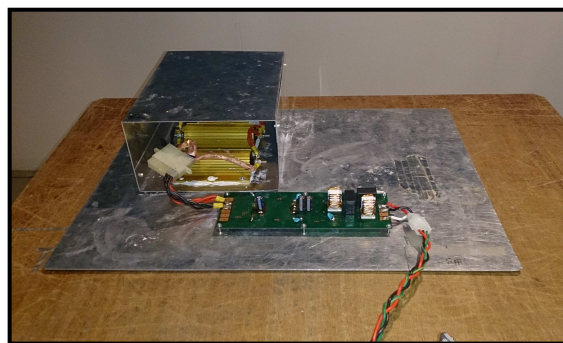
Model Name: CQHS250 Series

○ Photographs of Test Set-Up

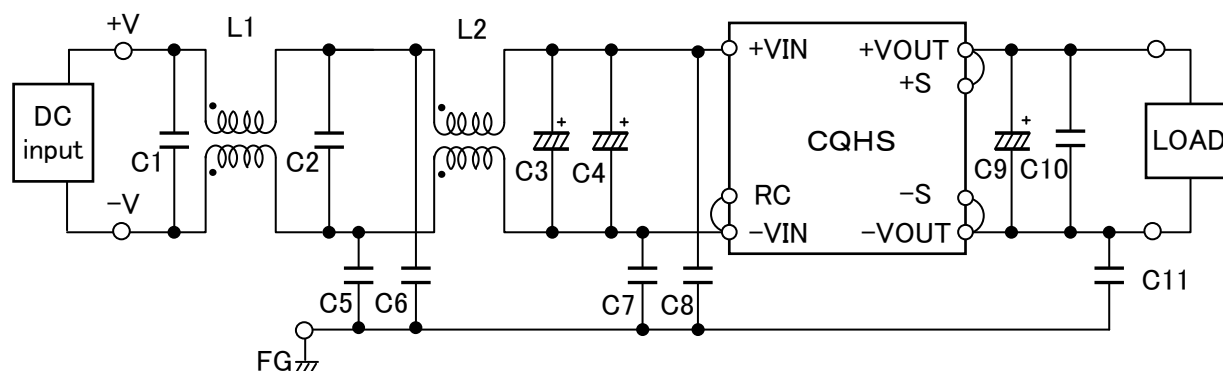
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : 0.5mH 15A Inductor (SC-15-05J NEC TOKIN)
- C1, C2 : 310V 2.2 μ F Film capacitor (OKAYA ELEC)
- C3, C4 : 100V 68 μ F Electlic capacitor (LXV NIPPON CHEMI-CON)
- C5, C6, C7, C8 : 250V 4700pF Ceramic capacitor (Type KY MURATA)
- C9 : CQHS2504832 50V 220 μ F Electlic capacitor (LXZ NIPPON CHEMI-CON)
CQHS2504850 100V 100 μ F Electlic capacitor (KY NIPPON CHEMI-CON)
- C10 : 100V 0.1 μ F Film capacitor (NITSUKO)
- C11 : 630V 0.068 μ F Film capacitor (NITSUKO)